

PUBLICLY AVAILABLE SPECIFICATION



**Electrostatics –
Part 5-6: Protection of electronic devices from electrostatic phenomena –
Process assessment techniques**



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IEC Secretariat
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

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Electrostatics – Part 5-6: Protection of electronic devices from electrostatic phenomena – Process assessment techniques

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CONTENTS

FOREWORD	4
1.0 PURPOSE, SCOPE, LIMITATION, and EXPERIENCE LEVEL REQUIRED	9
1.1 Purpose	9
1.2 Scope.....	9
1.3 Limitation	9
1.4 Experience Level Required	9
2.0 Referenced PUBLICATIONS	9
3.0 DEFINITIONS	10
4.0 Personnel Safety	10
5.0 Measurement Techniques FOR ESd Risk Assessment	10
6.0 ESD Robustness of ESDS ITEMS used in Processes	12
6.1 ESD Withstand Currents of Single Devices (Components)	13
6.1.1 Human Body Model	13
6.1.2 Discharge of Charged Conductors	13
6.1.3 Charged Device Model	14
6.2 ESD Withstand Currents of Electronic Assemblies	14
6.2.1 Discharge of Charged Personnel	14
6.2.2 Discharge of Charged Conductors	14
6.2.3 Discharge of Boards/Systems	15
7.0 Process Assessment Flow	15
7.1 General Considerations	15
7.2 Manual Handling Steps	16
7.2.1 Introduction	16
7.2.2 Parameter Limits for ESD Process Assessment in Manual Handling Steps	16
7.2.3 Detailed ESD Risk Assessment Flow	17
7.3 Conductors	18
7.3.1 Introduction	18
7.3.2 Parameter Limits for Process Assessment of Conductors	19
7.3.3 Detailed ESD Risk Assessment Flow	19
7.4 Charged ESDS Items	20
7.4.1 Introduction	20
7.4.2 Parameter Limits for Process Assessment of Charged ESDS Items	20
7.4.3 Detailed ESD Risk Assessment Flow	21
7.5 Risks Due to Process-Required Insulators	23
7.5.1 Introduction	23
7.5.2 Parameter Limits for Process Assessment of Process-Required Insulators	23
7.5.3 Detailed ESD Risk Assessment Flow	24
7.6 Process Assessment by ESD Event Detection	25
7.6.1 Introduction	25

7.6.2	General Procedure	26
7.6.3	Detailed ESD Risk Assessment Flow.....	26
ANNEX A (INFORMATIVE): Measurement TECHNIQUES And Equipment		28
A.1	General Considerations.....	28
A.2	Measurements of Grounding.....	28
A.3	Measurements of Electrostatic Fields	31
A.4	Measurements of Charges	32
A.5	Measurements of Electrostatic Voltages.....	33
A.6	Measurements of Discharge Events	37
A.7	Measurements of Discharge Currents.....	39
ANNEX B (INFORMATIVE) – PREPARATION: WHAT IS NECESSARY TO PREPARE AN EFFECTIVE PROCESS EVALUATION?		45
B.1	Measurement of Temperature, Humidity, and Basic Electrostatic Conditions	45
B.2	Further Hints for Preparation.....	45
ANNEX C (INFORMATIVE) – Risk Assessment and Mitigation.....		46
ANNEX D (INFORMATIVE) – ExampleS for defining limits in process assessment for Risks Due to Charged Personnel		47
ANNEX E (INFORMATIVE) – Example for CDM risk assessment in a semiconductor manufacturing line.....		49
ANNEX F (INFORMATIVE) – Bibliography		53
ANNEX g (INFORMATIVE) – revision History for ANSI/ESD Sp17.1		54
Table 1 – Overview of Possible Measurement Equipment Used for Different Scenarios to Assess ESD Risk.....		11
Table 2 – Peak Current Ranges of CDM Discharges of Small and Large Verification Modules for Oscilloscopes with a Bandwidth of 1 GHz and 6 GHz According to ANSI/ESDA/JEDEC JS-002.....		44
Table 3 – Recommended Measurement Locations During Process Assessment in Assembly (Pre-Assembly) of Devices		49
Table 4 – Recommended Measurement Locations During Process Assessment in Device Testing ..		50
Figure 1 – Direct (Best Correlation) and Indirect (Least Correlation) Measurements to Assess an ESD Risk.....		12
Figure 2 – Flow to Assess ESD Risk Induced by Personnel.....		18
Figure 3 – Flow to Assess the ESD Risk Induced by Conductors		20
Figure 4 – Flow to Assess the ESD Risk Induced by Charged ESDS Items		22
Figure 5 – Flow to Assess the ESD Risk Induced by Process-Required Insulators		25
Figure 6 – Flow to Assess the ESD Risk by Detecting the Electromagnetic Radiation Using ESD Event Detectors or Antennas and Oscilloscopes		27
Figure 7 – Examples of Current Probes		40
Figure 8 – Example of a 4-GHz Pellegrini Target		42
Figure 9 – Commercially Available CDM Test Head Used for Discharge Current Measurements.....		43
Figure 10 – Discharge Current Measured in the Field and During Device Qualification [8]		47
Figure 11 – Examples of Measurements During Semiconductor Assembly and Testing		50
Figure 12 – Schematic of Possible CDM-Like Scenarios During Device Testing		52

INTERNATIONAL ELECTROTECHNICAL COMMISSION

ELECTROSTATICS –

**Part 5-6: Protection of electronic devices from electrostatic phenomena –
Process assessment techniques**

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IEC PAS 61340-5-6 has been processed by IEC technical committee 101: Electrostatics.

It is based on ANSI/ESD SP17.1-2020. The structure and editorial rules used in this publication reflect the practice of the organization which submitted it.

The text of this PAS is based on the following document:

This PAS was approved for publication by the P-members of the committee concerned as indicated in the following document

Draft PAS	Report on voting
101/654/DPAS	101/663/RVDPAS

Following publication of this PAS, the technical committee or subcommittee concerned may transform it into an International Standard.

A list of all parts in the IEC 61340 series, published under the general title *Electrostatics*, can be found on the IEC website.

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***ESD Association Standard Practice for
the Protection of Electrostatic Discharge
Susceptible Items –
Process Assessment Techniques***

Approved November 17, 2020
EOS/ESD Association, Inc.



(This foreword is not part of EOS/ESD Association, Inc. Standard Practice ANSI/ESD SP17.1-2020)

FOREWORD

This standard practice¹ describes a set of methodologies, techniques, and tools that can be used to characterize a process where ESD sensitive (ESDS) items are handled. This document's procedures are meant to be used by those possessing knowledge and experience with electrostatic measurements. This document provides methods to determine the level of ESD risk that remains in the process after ESD protective equipment and materials are implemented.

These test methods' objective is to identify if potentially damaging ESD events are occurring or if significant electrostatic charges are generated on people, equipment, materials, components, or printed circuit board assemblies (PCBA) even though there are static control measures in place.

Sensitivities of items are characterized by industry-standard ESD testing and rated by their withstand voltages. This document is intended to provide methods to determine whether items of a given withstand voltage are at risk in the process.

The wide variety of ESD protective equipment and materials and the environment in which these items are used may require test setups different from those described in this document. Users of this standard practice may need to adapt the test procedure and setups described in Annex A to produce meaningful data for the user's application.

Organizations performing these tests will need to determine if on-going process characterization is necessary, and if so, the time interval between observations. It may also be important to make these observations when new products are introduced or when process changes occur. Examples of process changes may include tools, fixtures, equipment, new items/products, and additional manufacturing steps.

The topics below are not addressed in this document:

- Program Management: see ANSI/ESD S20.20 Protection of Electrical and Electronic Parts, Assemblies and Equipment (Excluding Electrically Initiated Explosive Devices)
- Compliance Verification: see ESD TR53-01 Compliance Verification of ESD Protective Equipment and Materials
- Troubleshooting: ESD TR53-01
- ESD Program Certification: see ANSI/ESD S20.20 Certification Program at www.esda.org

This document was designated ANSI/ESD SP17.1-2020 and approved on November 17, 2020.

¹ **ESD Association Standard Practice:** A procedure for performing one or more operations or functions that may or may not yield a test result. Note, if a test result is obtained it may not be reproducible.